

Title (en)
Probe microscope

Title (de)
Sondenmikroskop

Title (fr)
Microscope de sonde

Publication
EP 2278264 B1 20140625 (EN)

Application
EP 10166608 A 20100621

Priority
JP 2009164589 A 20090713

Abstract (en)
[origin: EP2278264A1] A probe microscope includes a cantilever 2 having a probe 21 for contact with an object, first and second displacement detection optical systems 3 and 4, and an object lens 7. The first displacement detection optical system 3 includes a first light source 31 and a first displacement detecting section that detects displacement of the cantilever 2. The second displacement detection optical system 4 includes a second light source 41 and a second displacement detecting section that detects displacement of the object. The object lens 7 is provided between the cantilever 2 and the first light source 31 and between the cantilever 2 and the second light source 41. The object lens 7 has a focal position for the light that is emitted from the first light source 31 and has a first wavelength at the position of the cantilever 2 and has a focal position for the light that is emitted from the second light source 41 and has a second wavelength at the position of the object.

IPC 8 full level
G01B 9/02 (2006.01); **G01Q 20/02** (2010.01)

CPC (source: EP US)
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